

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/902,752	BAUDOIN ET AL.	
Examiner	Art Unit	
Thion D. Tran	2616	

	SEARCHED					
Class	Subclass	Date	Examiner			
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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See search printout		7/8/2996	π	

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
EAST (USPGPUB, USPAT, USOCR, EPO, DERWENT) 370/322, 395.43, 468; 455/450-452.2. Consulted with Nguyen Vo 05/01/2006	7/8/2006	тт
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